Docket No.: 60188-809 **PATENT**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277

Michinari YAMANAKA : Confirmation Number:

Serial No.: : Group Art Unit:

Filed: March 24, 2004 : Examiner:

For: DRY ETCHING APPARATUS AND DRY ETCHING METHOD

INFORMATION DISCLOSURE STATEMENT

Mail Stop IDS Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In a ccordance with the provisions of 3 7 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The relevance of the six references listed on attached Form 1449 is discussed in the present specification.

Serial No.:

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

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(202) 756-8000 MEF:mcw Facsimile: (202) 756-8087 **Date: March 24, 2004**

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INFO	CIT	ATION DISCLOS CATION IN AN PPLICATION	ATTY. DOCKET NO. 60188-809	SERIAL NO.					
				APPLICANT Michinari YAMANA	APPLICANT Michinari YAMANAKA				
(PTO-1449)				FILING DATE March 24, 2004					
			U.S. PATE	NT DOCUMENTS	1				
EXAMINER'S	T	Document Number	Publication Da	te Name of Patentee or Appl	Name of Patentee or Applicant of Cited		Pages, Columns, Lines, Where		
INITIALS	CITE NO.	Number-Kind Code2 (if known)	MM-DD-YYY)		icant or offed		es, Columns, Lines, Where evant Passages or Relevant Figures Appear		
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EXAMINER'S	l ·	Foreign Patent Document	Publication Date		Pages, Colum	ns. Lines	Translation		
INITIALS	CITE NO.	Country Codes -Number 4 -Kind Codes (if known)	MM-DD-YYYY		Where Relevant Figures Appear		Yes	No	
	A	2002-009042	01/11/2002	SEMICONDUCTOR LEADING EDGE TECHNOLOGIES INC			English Abstract (Japanese Patent N 3333177)	w/	
		07-245292	09/19/1995	TOKYO ELECTRON LTD TOSHIBA CORP		·	Japanese (w/ English Abstrac	,	
		08-186096	07/16/1996	FUJITSU LTD FUJITSU VLSI LTD			Japanese (w/ English Abstract	:)	
	Α	P2002-09048	01/11/2002	MATSUSHITA ELECTRIC IND CO LTD			Japanese (w/ English Abstrac)	
	A	P2002-164323	06/07/2002	SEMICONDUCTOR LEADING EDGE TECHNOLOGIES INC	i i		Japanese (w/ English Abstrac	()	
	A	P2002-190466	07/05/2002	SEMICONDUCTOR LEADING EDGE TECHNOLOGIES INC			Japanese (w/ English Abstract)	
				nor, Title, Date, Pertinent Pages, E					
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.